

## Description

The Power MOSFET is fabricated using the advanced planar VDMOS technology. The resulting device has low conduction resistance, superior switching performance and high avalanche energy.

## Features

- ◆ Low  $R_{DS(on)}$
- ◆ Low gate charge (typ.  $Q_g = 50.5 \text{ nC}$ )
- ◆ 100% UIS tested
- ◆ RoHS compliant

## Applications

- ◆ Electronic ballast
- ◆ Switched mode power supplies.
- ◆ UPS.

## Product Summary

$V_{DSS}$	500V
$I_D$	18A
$R_{DS(on),max}$	0.28 $\Omega$
$Q_{g,typ}$	50.5 nC

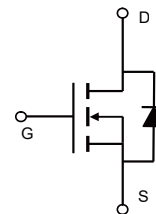
## Pin Configuration



TO-220F



TO-220C



Schematic

## Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-Source Voltage	$V_{DSS}$	500	V
Continuous drain current ( $T_C = 25^\circ\text{C}$ )	$I_D$	18	A
( $T_C = 100^\circ\text{C}$ )		11.4	A
Pulsed drain current <sup>1)</sup>	$I_{DM}$	72	A
Gate-Source voltage	$V_{GSS}$	$\pm 30$	V
Avalanche energy, single pulse <sup>2)</sup>	$E_{AS}$	810	mJ
Power Dissipation C C C TO-220F /TO-220C ( $T_C = 25^\circ\text{C}$ )	$P_D$	37.5	W
Power Dissipation C C TO-220C ( $T_C = 25^\circ\text{C}$ )		232	W
Operating junction and storage temperature range	$T_J, T_{STG}$	-55 to +150	$^\circ\text{C}$
Continuous diode forward current	$I_S$	18	A
Diode pulse current	$I_{S,pulse}$	72	A

## Thermal Characteristics

Parameter	Symbol	Value		Unit
		C C C TO-220F /TO-220F	C C C TO-220	
Thermal resistance, Junction-to-case	$R_{\theta JC}$	3.3	0.54	$^\circ\text{C/W}$
Thermal resistance, Junction-to-ambient <sup>3)</sup>	$R_{\theta JA}$	62.5	62.5	$^\circ\text{C/W}$

## Package Marking and Ordering Information

Device	Device Package	Marking	Units/Tube
VSM18N50-TF	TO-220F	VSM18N50-TF	50
VSM18N50-TC	TO-220C	VSM18N50-TC	50

## Electrical Characteristics

 $T_c = 25^{\circ}\text{C}$  unless otherwise noted

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Static characteristics						
Gate threshold voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =0.25 mA	2	-	4	V
Drain cut-off current	I <sub>DSS</sub>	V <sub>DS</sub> =500 V, V <sub>GS</sub> =0 V, T <sub>J</sub> = 25°C T <sub>J</sub> = 125°C	- -	-	1 100	μA
Gate leakage current, Forward	I <sub>GSSF</sub>	V <sub>GS</sub> =30 V, V <sub>DS</sub> =0 V	-	-	100	nA
Gate leakage current, Reverse	I <sub>GSSR</sub>	V <sub>GS</sub> =-30 V, V <sub>DS</sub> =0 V	-	-	-100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10 V, I <sub>D</sub> =9 A	-	0.24	0.28	Ω
Dynamic characteristics						
Input capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz	-	3045	-	pF
Output capacitance	C <sub>oss</sub>		-	284	-	
Reverse transfer capacitance	C <sub>rss</sub>		-	12	-	
Turn-on delay time	t <sub>d(on)</sub>	V <sub>DD</sub> = 250 V, I <sub>D</sub> = 18 A R <sub>G</sub> = 10 Ω, V <sub>GS</sub> =15 V	-	17.5	-	ns
Rise time	t <sub>r</sub>		-	42	-	
Turn-off delay time	t <sub>d(off)</sub>		-	101	-	
Fall time	t <sub>f</sub>		-	15.5	-	
Gate charge characteristics						
Gate to source charge	Q <sub>gs</sub>	V <sub>DD</sub> =400 V, I <sub>D</sub> =18 A, V <sub>GS</sub> =0 to 10 V	-	12.7	-	nC
Gate to drain charge	Q <sub>gd</sub>		-	15.8	-	
Gate charge total	Q <sub>g</sub>		-	50.5	-	
Gate plateau voltage	V <sub>plateau</sub>		-	5	-	V
Reverse diode characteristics						
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0 V, I <sub>F</sub> =18 A	-	-	1.3	V
Reverse recovery time	t <sub>rr</sub>	V <sub>R</sub> =400 V, I <sub>F</sub> =18 A, dI <sub>F</sub> /dt=100 A/μs	-	368	-	ns
Reverse recovery charge	Q <sub>rr</sub>		-	4.6	-	μC
Peak reverse recovery current	I <sub>rrm</sub>		-	25	-	A

Notes:

1. Pulse width limited by maximum junction temperature.
2.  $L=5\text{mH}$ ,  $I_{AS} = 18\text{A}$ , Starting  $T_j= 25^{\circ}\text{C}$ .
3. The value of  $R_{thJA}$  is measured by placing the device in a still air box which is one cubic foot.

## Electrical Characteristics Diagrams

Figure 1. Typical Output Characteristics

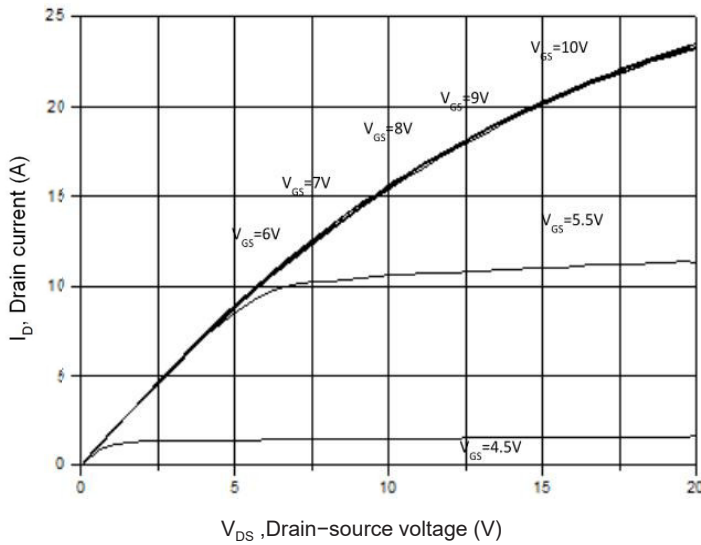


Figure 2. Transfer Characteristics

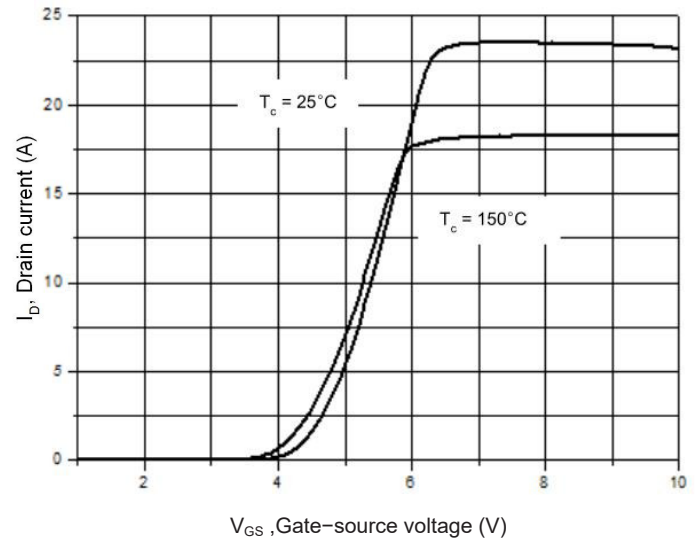


Figure 3. On-Resistance Variation vs. Drain Current

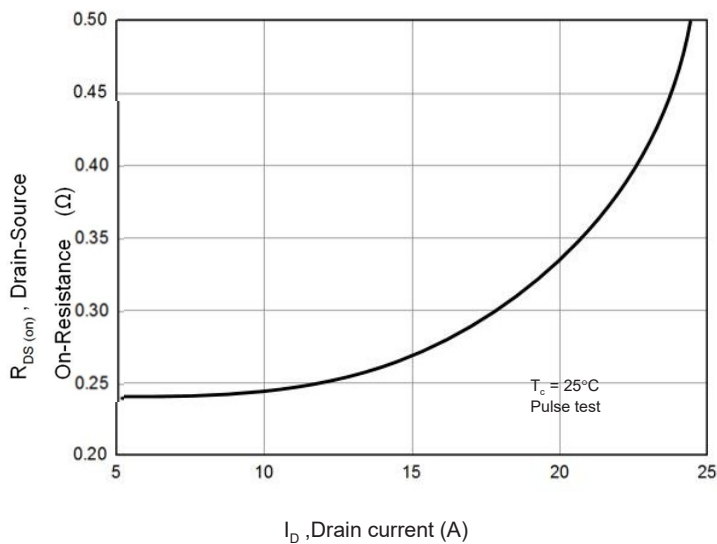


Figure 4. Threshold Voltage vs. Temperature

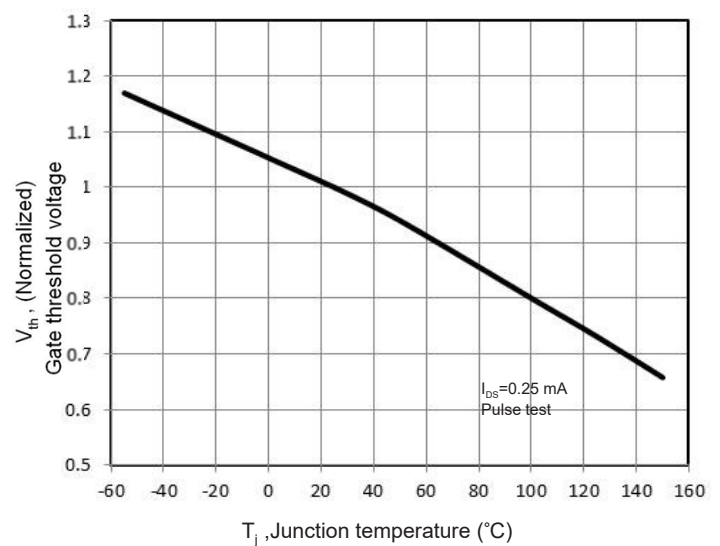


Figure 5. Breakdown Voltage vs. Temperature

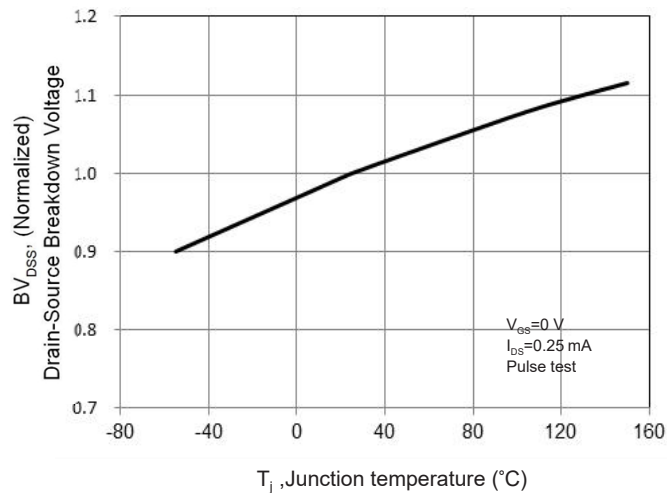


Figure 6. On-Resistance vs. Temperature

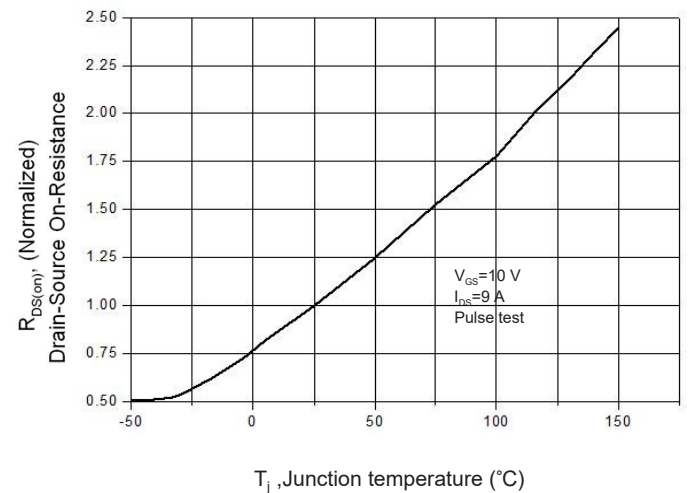


Figure 7. Capacitance Characteristics

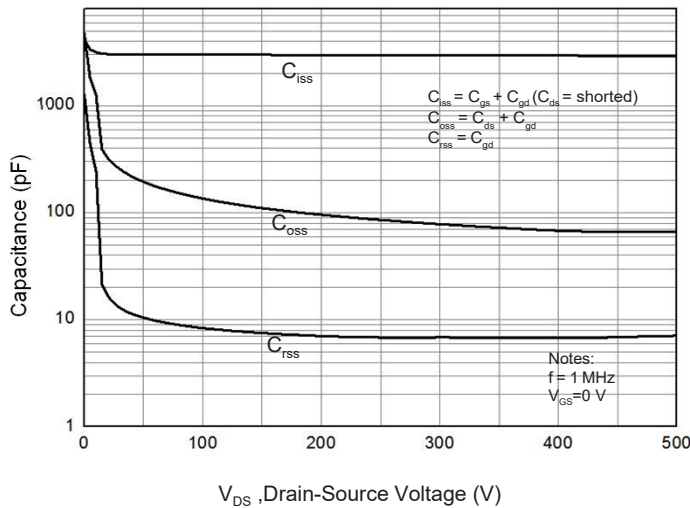


Figure 8. Gate Charge Characteristics

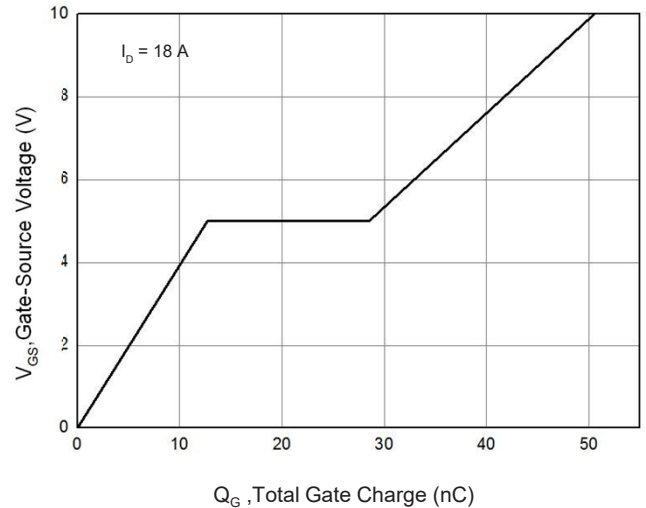


Figure 9: Safe Operating Area (TO-220F/TO-220NF)

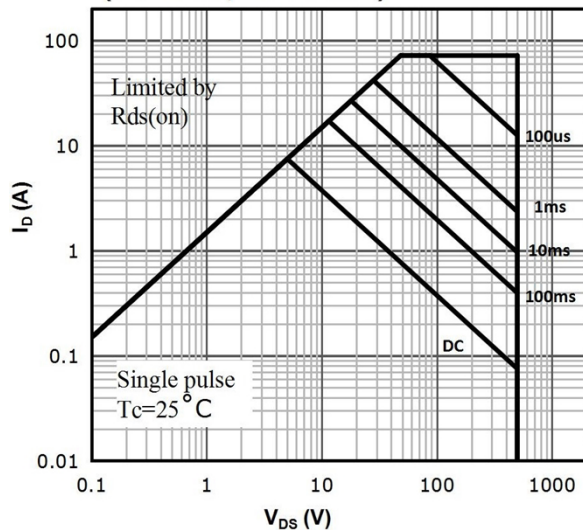


Figure 10: Safe Operating Area (TO-220)

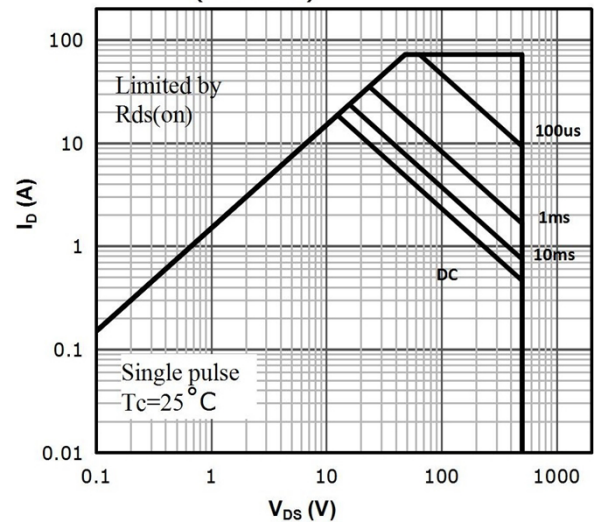
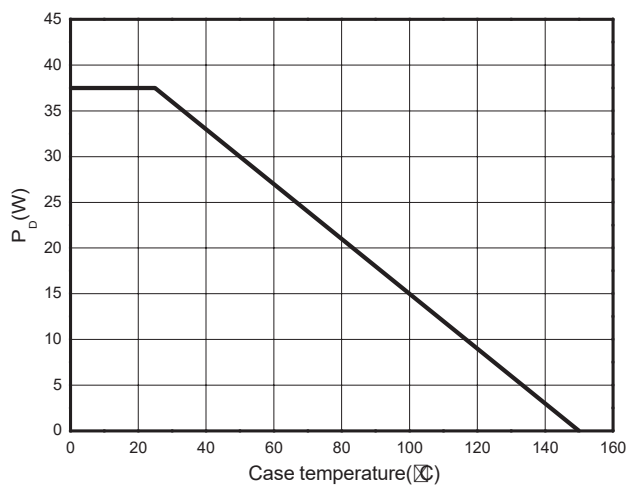
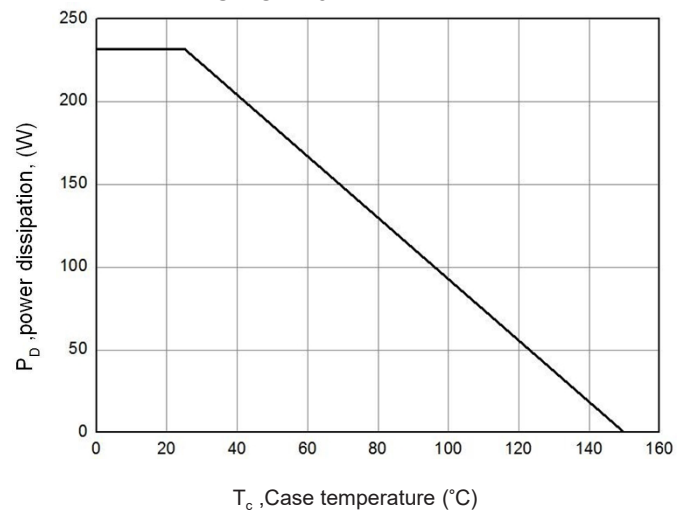

Figure 11. Power Dissipation vs. Temperature  
C TO-220F /TO-220F

Figure 12. Power Dissipation vs. Temperature  
C TO-220


Figure 13. Continuous Drain Current vs. Temperature

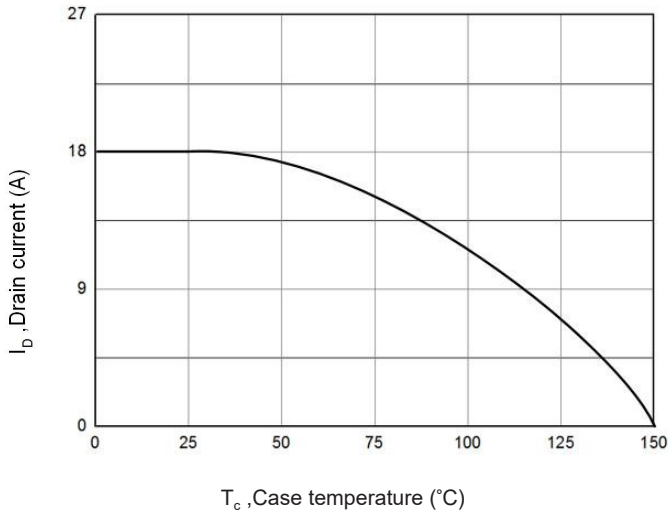


Figure 14. Body Diode Transfer Characteristics

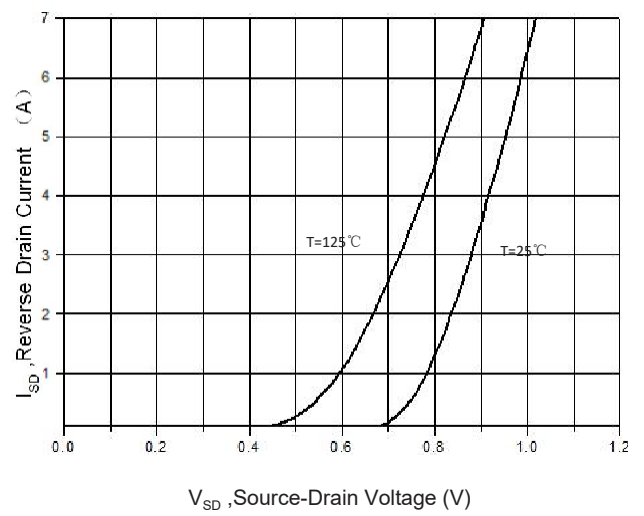


Figure 15. Transient Thermal Impedance, Junction to CaseC TO-220F /TO-220F

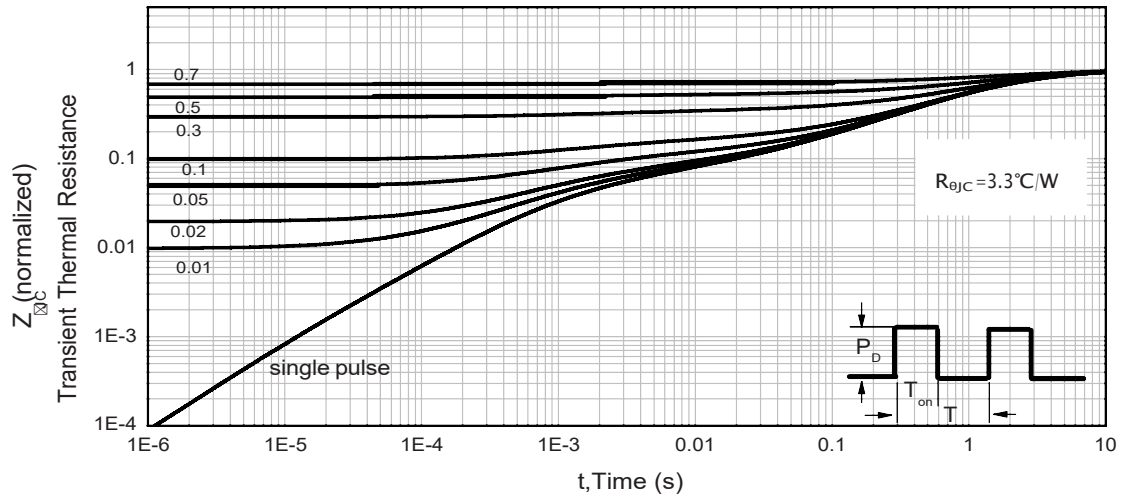
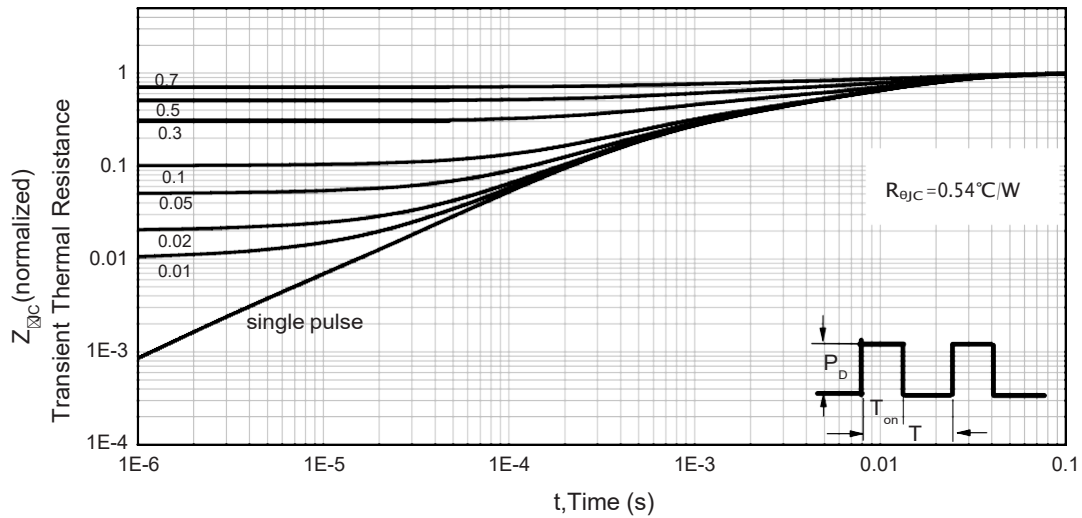
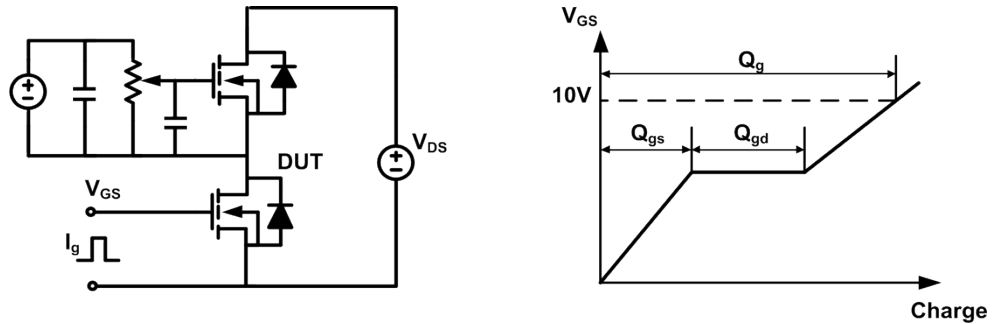


Figure 16. Transient Thermal Impedance, Junction to CaseC TO-220

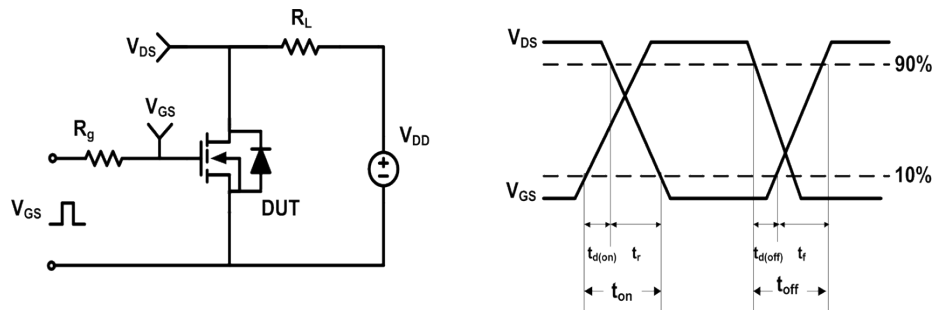


## Test Circuit & Waveforms

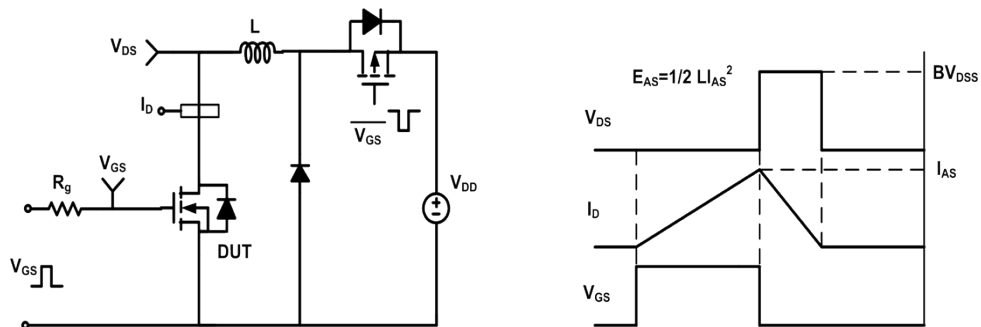
### Gate Charge Test Circuit & Waveform



### Resistive Switching Test Circuit & Waveform



### Unclamped Inductive Switching (UIS) Test Circuit & Waveform



### Diode Recovery Test Circuit & Waveform

